

Title (en)

SECONDARY ION MASS SPECTROMETER AND SECONDARY ION MASS SPECTROMETRIC METHOD

Title (de)

SEKUNDÄRIONEN-MASSENSPEKTROMETER UND SEKUNDÄRIONEN-MASSENSPEKTROMETRISCHES VERFAHREN

Title (fr)

SPECTROMÈTRE DE MASSE À IONISATION SECONDAIRE, ET PROCÉDÉ DE SPECTROMÉTRIE DE MASSE À IONISATION SECONDAIRE

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Application

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Abstract (en)

[origin: WO2017042293A1] The invention relates to a secondary ion mass spectrometer and to a method for the secondary ion mass spectrometric analysis of a sample. A large number of secondary ion mass spectrometers is known in the prior art. Among said secondary ion mass spectrometers, the time-of-flight secondary ion mass spectrometer (ToF-SIMS) in particular is of interest.

IPC 8 full level

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